	Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/669,177	SHEN ET AL.	
Examiner	Art Unit	
R. Stephen Dildine	2133	

SEARCHED				
Class	Subclass	Date	Examiner	
714	752, 791 and 794	5/2/2006	RSD	
Н03М	13/11	5/3/2006	RSD	
Н03М	13/13	5/3/2006	RSD	
нозм	13/39	5/3/2006	RSD	
Update	all above	8/29/2006	RSD	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	, see Search printout	8/29/2006	RSD	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB (see Search History printout)	5/3/2006	RSD	
IEEEXplore	5/3/2006	RSD	
Update all above	8/29/2006	RSD	
Inventors' name search	5/3/2006	RSD	